**Product data sheet** 

## 1. General description

Planar passivated high commutation three quadrant triac in an IITO220 internally insulated plastic package intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. This "series B" triac will commutate the full RMS current at the maximum rated junction temperature without the aid of a snubber. This device has high  $T_j$  operating capability and an internally isolated mounting base.

### 2. Features and benefits

- · 3Q technology for improved noise immunity
- · High commutation capability with maximum false trigger immunity
- High junction operating temperature capability ( $T_{j(max)} = 150$  °C)
- · High surge capability
- · Isolated mounting base with 2500 V (RMS) isolation
- · Least sensitive gate for highest noise immunity
- · Planar passivated for voltage ruggedness and reliability
- · Triggering in three quadrants only
- · Very high immunity to false turn-on by dV/dt

## 3. Applications

- · Electronic thermostats (heating and cooling)
- · High power motor controls
- · Rectifier-fed DC inductive loads e.g. DC motors and solenoids

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit		
Absolute	Absolute maximum rating							
$V_{DRM}$	repetitive peak off-state voltage		-	-	800	V		
I <sub>T(RMS)</sub>	RMS on-state current	square-wave pulse; T <sub>mb</sub> ≤ 116 °C; Fig. 1; Fig. 2; Fig. 3	-	-	12	А		
I <sub>TSM</sub>	non-repetitive peak forward current	full sine wave; $t_p$ = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	-	-	140	А		
		full sine wave; $t_p = 16.7 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$	-	-	153	А		
T <sub>j</sub>	junction temperature		-	-	150	°C		
Static cha	aracteristics		,	1				
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G + T_j = 25 \text{ °C; } Fig. 7$	2	-	50	mA		
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G T_j = 25 \text{ °C; } Fig. 7$	2	-	50	mA		
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-} $ $T_j = 25 \text{ °C; } Fig. 7$	2	-	50	mA		

3Q Triad

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	60	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 18 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.3	1.5	V
Dynamic	characteristics				'	
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	1000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	600	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 20 V/µs; gate open circuit; snubberless condition	20	-	-	A/ms
		$V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 20 V/µs; gate open circuit; snubberless condition	8	-	-	A/ms

## 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1	mb	NI
2	T2	main terminal 2		T2—T1
3	G	gate		sym051
mb	n.c	mounting base; isolated	1 2 3 1 2 3 A E	

# 6. Ordering information

### **Table 3. Ordering information**

Type number	Package name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BTA412Y-800B	IITO220	BTA412Y-800B,127	Tube	50	SOT78D (A)	07-July-2010
					IITO220E (E)	15-Dec-2017

# 7. Marking

#### **Table 4. Marking codes**

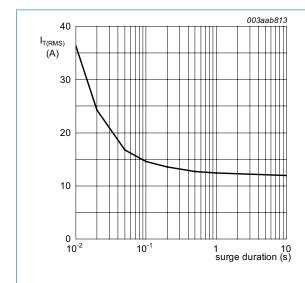
Type number	Marking codes		
	Assembly factory: A	Assembly factory: E	
BTA412Y-800B	BTA412Y 800B	BTA412Y 800B	
	PJAxxxx xx	PJExxxx xx	

# 8. Limiting values

#### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{mb} \le 116$ °C; <u>Fig. 1</u> ; <u>Fig. 2</u> ; <u>Fig. 3</u>	-	12	А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p$ = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	-	140	А
		full sine wave; $t_p = 16.7 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$	-	153	А
I <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10ms; sine wave	-	98	A <sup>2</sup> /s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 100mA	-	100	A/µs
I <sub>GM</sub>	peak gate current		-	2	А
P <sub>GM</sub>	peak gate power		-	5	W
P <sub>G(AV)</sub>	average gate power	over any 20 ms period	-	0.5	W
T <sub>stg</sub>	storage temperature		-40	150	°C
T <sub>j</sub>	junction temperature		-	150	°C



f = 50Hz; T<sub>mb</sub> = 116 °C Fig. 1. RMS on-state current as a function of surge duration; maximum values

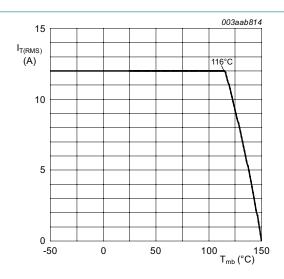
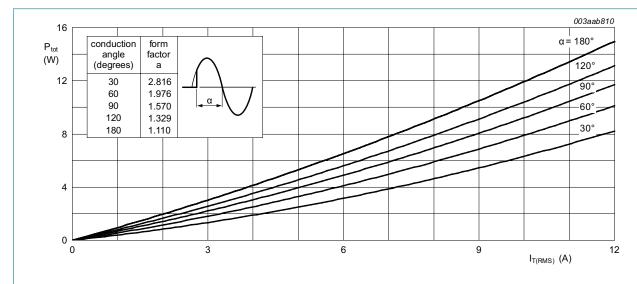


Fig. 2. RMS on-state current as a function of mounting base temperature; maximum values



 $\alpha$  = conduction angle

 $a = form \ factor = I_{T(RMS)} / I_{T(AV)} \\ Fig. \ 3. \quad Total \ power \ dissipation \ as \ a \ function \ of RMS \ on-state \ current; \ maximum \ values$ 

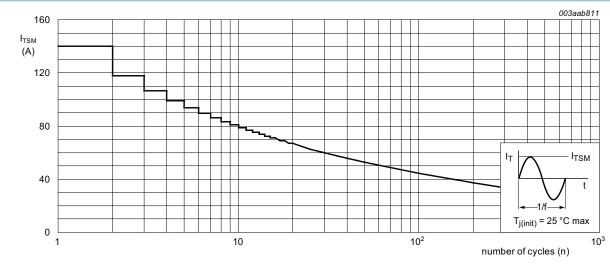
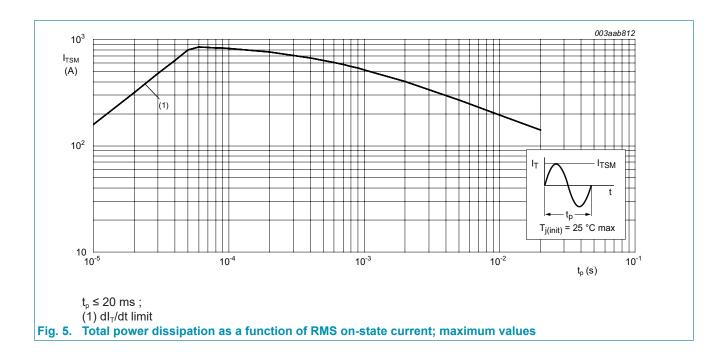


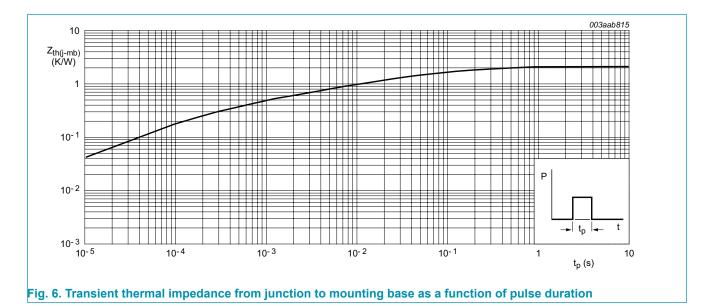
Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



### 9. Thermal characteristics

**Table 5. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-mb)}}$	thermal resistance from junction to mounting base	full cycle; Fig. 6	-	-	2.1	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient free air	in free air	-	60	-	K/W



### 10. Isolation characteristics

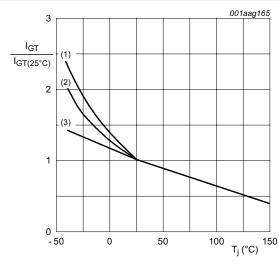
**Table 6. Isolation characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>isol(RMS)</sub>	RMS isolation voltage	50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
C <sub>isol</sub>	isolation capacitance	from cathode to external heatsink	-	10	-	pF

## 11. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics		'			'
l <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	2	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{ G-;} $ $T_j = 25 \text{ °C; } Fig. 7$	2	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 7$	2	-	50	mA
I <sub>L</sub>	latching current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	60	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2+ G-;}$ $T_j = 25 \text{ °C; Fig. 8}$	-	-	90	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	60	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	60	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 18 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.3	1.5	V
V <sub>GT</sub> gate	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.8	1	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 ^{\circ}\text{C}$	0.25	0.4	-	V
$I_D$	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 125 °C	-	0.1	0.5	μΑ
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	0.4	2	mA
Dynamic o	characteristics		'			'
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_{j}$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	1000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	600	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ gate open circuit};$ snubberless condition	20	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 20 \text{ V}/\mu\text{s}; \text{ gate open circuit};$ snubberless condition	8	-	-	A/ms





(2) T2+ G-(3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

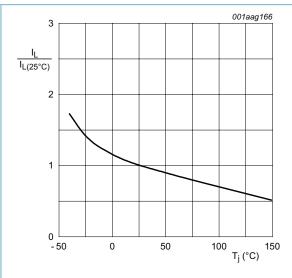


Fig. 8. Normalized latching current as a function of junction temperature

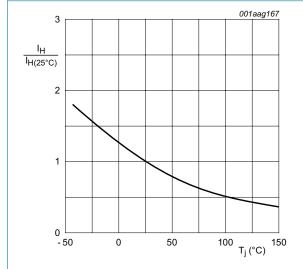
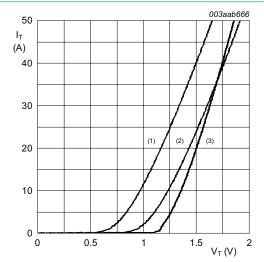


Fig. 9. Normalized holding current as a function of junction temperature

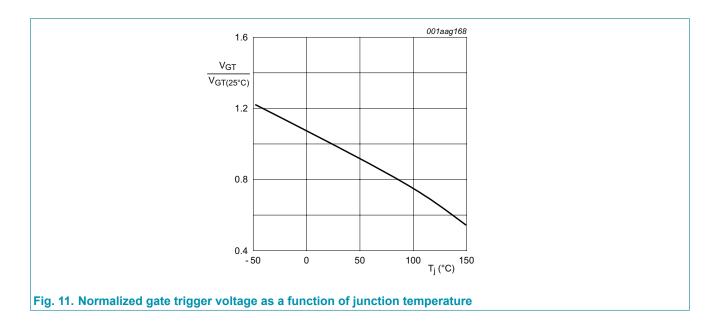


 $V_o$  = 1.024 V;  $R_s$  = 0.021  $\Omega$ 

(1)  $T_j = 125$  °C; typical values (2)  $T_j = 125$  °C; maximum values

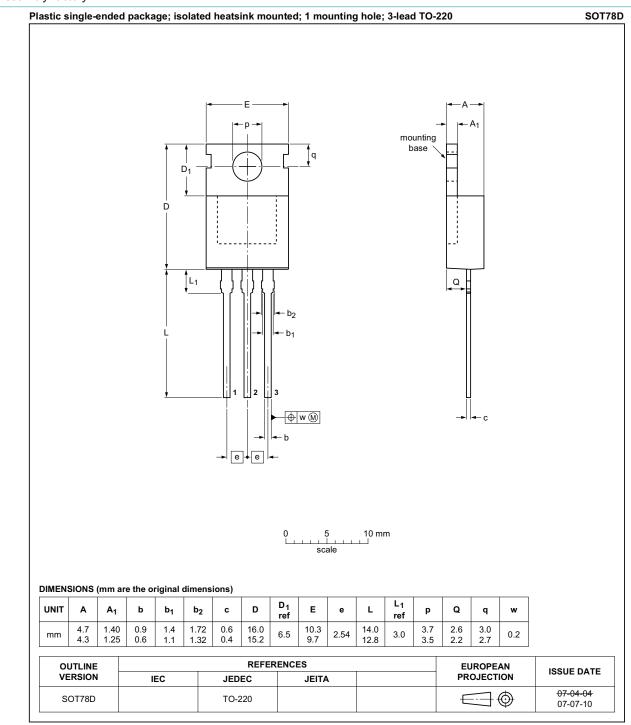
(3) T<sub>i</sub> = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

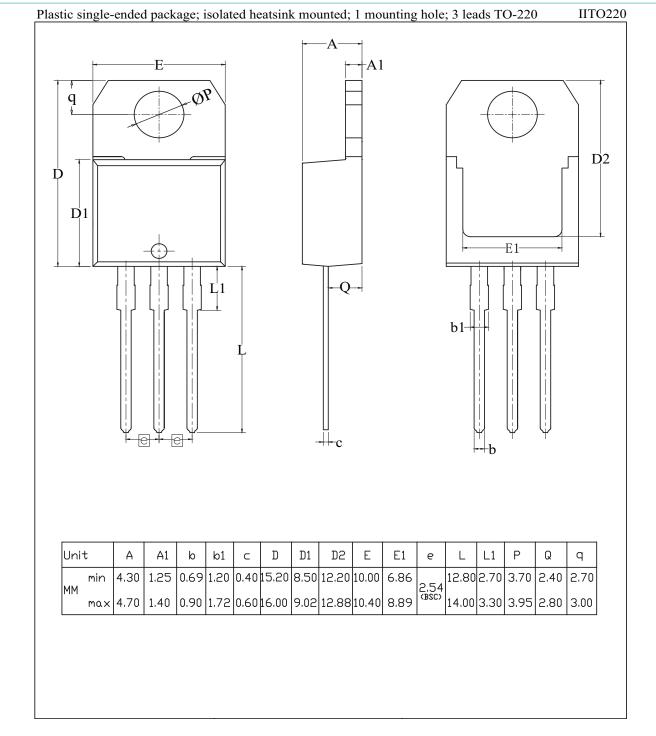


# 12. Package outline

Assembly factory: A



#### Assembly factory: E



### 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 30 July 2021

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